

8th High Level Expert Meeting Asphere Metrology

Key Dates

- Abstract Deadline: October 15, 2016
- Decision on the Abstract Acceptance:
- November 1, 2016 February 12, 2016 January 15, 2017
- Extended Abstract Deadline: February 12, 2016
- Deadline Application for Industrial Exhibition:
- Date of HLEM:
- Venue:
- Attendance Fee:

PTB Braunschweig, Gemany Lecturers: € 150,- (1st person) Members: € 150,-Non-Members: € 525,-Please pay ofter receiving the invoice.

March 14 - 15 2017

Included:

Conference participation, Proceedings, Conference dinner, Refreshments during conference









March 14 - 15, 2017 at Physikalisch-Technische Bundesanstalt, Germany



Background

Topics

High-Level Expert Meetings (HLEM) and workshops, developers, manufacturers and users have confirmed the great interest in asphere metrology.

Both the introduced measurement systems as well as the results of round robin comparison measurements show the enormous potential of this field of technology. In additi-

on, a great need for comparability, standardization and proximity to users was also pointed out.

Our upcoming 8th HLEM 2017 is dedicated to the presentation, discussion and dissemination of new



developments and recent scientific results in asphere and free form metrology for reflective and transmissive surfaces. With this broader scope we aim to supplement our previous events while also addressing asphere and free form metrology to interested scientists, developers and manufacturers.

Topics of particular interest are:

- New developments in measuring techniques for aspherical, free form and cylindrical lenses
- Measurements of small precision optics (as used for endoscopy, mobiles, sensors ...)
- In situ-measurements in complex UP processing lines for aspherical or freeform surfaces
- Clamping technologies for measurements in aspherical lens production
- Standardization in the description of aspheres and freeform surfaces
- Measurements of aspherical surfaces of moulding tools for glass and plastic lenses
- The influence of coatings on the measurement of aspheric and freeform lenses
- Other topics related to asphere and free form metrology or production



Authors who intend to give a presentation should specify the title and the topic from the list above together with a 200 word abstract in English.